TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ( -MOSIV)

# 2SK3799

Switching Regulator Applications

TOSHIBA

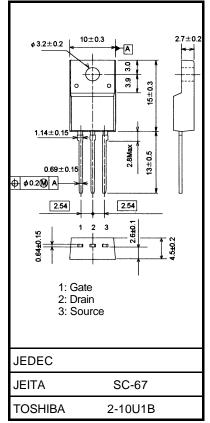
- Low drain-source ON resistance: RDS (ON) = 1.0 (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 7.0S$  (typ.)
- Low leakage current:  $I_{DSS} = 100 \ \mu A (V_{DS} = 720 \text{ V})$
- Enhancement-mode:  $V_{th} = 2.0 \sim 4.0 V (V_{DS} = 10 V, I_D = 1 mA)$

### Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	900	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		V <sub>DGR</sub>	900	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	ΙD	(8)		
	Pulse (t = 1 ms) (Note 1)	ldр	(24)	A	
Drain power dissipat	ion (Tc = 25°C)	PD	(47)	W	
Single pulse avalanc	ne energy (Note 2)	E <sub>AS</sub>	TBD	mJ	
Avalanche current		I <sub>AR</sub>	(8)	А	
Repetitive avalanche	energy (Note 3)	E <sub>AR</sub>	TBD	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

### **Preliminary**

Unit: mm



Weight : 1.7 g (typ.)

#### **Thermal Characteristics**

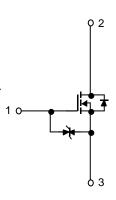
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	(2.66)	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Please use devices on conditions that the channel temperature is below 150°C.

Note 2: TBD

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.



Electrical Characteristics (Ta = 25°C)

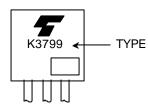
## **Preliminary**

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Characteristics Sym		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ
Gate-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30		_	V
Drain cut-off curr	ent	IDSS	$V_{DS} = 720 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			100	μA
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	900		_	V
Gate threshold v	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	2.0		4.0	V
Drain-source ON	l resistance	R <sub>DS (ON)</sub>	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 4 \text{ A}$		(1.0)	(1.4)	Ω
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_{D} = 4 \text{ A}$		7.0		S
Input capacitance		C <sub>iss</sub>			2200		
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 25 V, V_{GS} = 0 V, f = 1 MHz$		45		pF
Output capacitance		C <sub>oss</sub>			190		
Switching time	Rise time	tr	$V_{GS}^{10 V}$ $V_{GS}^{10 V}$ $V_{GS}^{10 V}$ $V_{GS}^{10 V}$ $V_{GS}^{10 V}$ $R_{L} = 100\Omega$ $V_{DD} = 400 V$	_	25	_	ns
	Turn-on time	t <sub>on</sub>			65		
	Fall time	t <sub>f</sub>		_	20		
	Turn-off time	t <sub>off</sub>	Duty $\leq$ 1%, t <sub>w</sub> = 10 µs		120	_	
Total gate charge		Qg			60		
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V},  V_{GS} = 10 \text{ V},  I_D = 8 \text{ A}$		34		nC
Gate-drain charge		Q <sub>gd</sub>	]		26		

### Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	—		_	(8)	А
Pulse drain reverse current (Note 1)	<b>I</b> DRP	—		_	(24)	А
Forward voltage (diode)	V <sub>DSF</sub>	$I_{DR} = 8 \text{ A}, V_{GS} = 0 \text{ V}$	_		-1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 8 \text{ A}, V_{GS} = 0 \text{ V},$	_	1.4		μs
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/µs	_	16		μC

### Marking



Lot Number



Month (Starting from Alphabet A) Year (Last Number of the Christian Era)

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